

Search Notes

Application/Control No.

10/774,690

Examiner

Leith A. Al-Nazer

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
315	111.21- 111.71	1/19/2006	LA
422	168-183	1/19/2006	LA
422	186.04	1/19/2006	LA
422	186.18	1/19/2006	LA
423	210	1/19/2006	LA
423	235	1/19/2006	LA
423	245.1	1/19/2006	LA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
315	111.21 - 111.71	1/19/06	La
422	168 - 183	1/19/06	La
422	186.04, 186.18	1/19/06	La
423/210, 235, 245.1		1/19/06	La

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST prior art text search (see "Examiner Search Notes")	1/19/2006	LA
EAST interference text search (see "Examiner Search Notes")	1/19/2006	LA